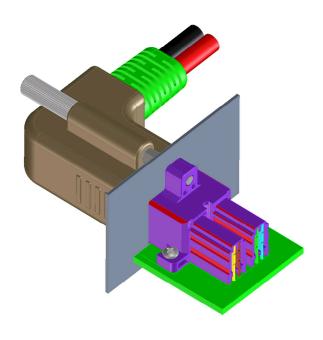
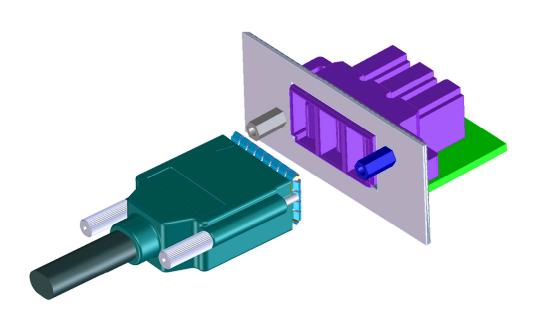


## **GUARDIAN CONNECTOR SYSTEM**





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DOCUMENT	NUMBER:	CREATED / REVISED BY:	CHECKED BY:	APPROVED BY:
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## PRODUCT SPECIFICATION

### **TABLE OF CONTENTS:**

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- 2.0 SUMMARY OF RESULTS
- 3.0 DOCUMENTS & SPECIFICATIONS
  - 3.1 Testing Procedure & Sequences
  - 3.2 Other Documents
- 4.0 MECHANICAL PERFORMANCE
  - 4.1 Component Level
  - 4.2 Free Hanging Load Test
- 5.0 ELECTRICAL REQUIREMENTS
  - 5.1 Crimp Stress Test-Millivolt Drop
  - **5.1.1 Crimp Stress Acceptance Criteria**
  - 5.2 Electrical Performance and Rating
  - 5.3 Temperature Rise Current Charts
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	TEMPLATE FILENAME: PRODUCT_SPEC[SIZE_A](V.1).DOC				

### 1.0 SCOPE

The specification covers the test sequence performance of the high current wire-to-board interconnect

#### 2.0 SUMMARY OF RESULTS

The product meets all the Mechanical, Electrical and Environmental test criteria at component and harness level, and is considered a qualified product.

### 3.0 DOCUMENTS AND SPECIFICATIONS

#### 3.1 **Testing Procedure & Sequences:**

Item	Test Report	Test Description
1	TR-1.8582	Qualification Test Per EIA-364-1000 Group 1,2,3, & 5
2	TR-1.8583	Electrical Crimp Qualification of 8 & 10 AWG
3	TR-1.8584	Construction analysis
4	TR-1.8733	Harness Pull Force and Torque Retention Test, in mated condition
5	TR-1.8570	T-Rise Test per EIA-364B
6	TR-1.8595	Normal Force Analysis
7	63801-7900	Mech. Crimp Qualification
8		EIA-364-1000 Group 4 Mixed Flowing Gases
9	TR-1.8931	Hot-mating/Resistance to Arc

#### 3.2 Other Documents:

See series specific sales drawings for additional information.

HEADER	2 CKT	46817 SERIES
HEADER	3 CKT	46817 SERIES
HARNESS	2 CKT	68790 SERIES
HARNESS	3 CKT	111119 SERIES

Ref. terminal in harness - 46819-\*\*\*\*

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## PRODUCT SPECIFICATION

### 4.0 MECHANICAL PERFORMANCE

### 4.1 MECHANICAL PERFORMANCE AT COMPONENT LEVEL

EQUIPMENT/FIXTURE	TEST DESCRIPTION			TEST	RESU	JLT		
Force Gauge	Terminal Retention to the Housing (Header) per EIA-364-29		Avg.(3 (	· ·			13.83 N 0.56	
Solder Pot	Solderability Test (Header) per EIA- 364-52		N	leets 95%	min C	Coverage		
X-Ray Fluoroscope	Plating Verification (Plug & Crimp Terminal)	Meets Specification						
Instron	Normal Force per EIA-364-04, Method	3.90 g (Avg)/Beam @ 0.45 mm deflection						
		1 <sup>st</sup> Cycle Insertion Force (Newtons)		Wi	Withdrawal Force (Newtons)			
Instron			1 ckt	2 ckt	3 ck	t 1 ckt	2 ckt	3 ck
	Insertion/Withdrawal Force per EIA-364-13	Min	7.23	11.27	26.7	1 6.86	10.31	28.2
		Max	9.23	19.11	36.6	8.53	19.12	34.3
		Avg	7.92	15.60	31.0	6 7.36	15.87	30.7
		Std Dev	0.68	3.15	3.70	0.68	3.85	2.20
Force Gauge	Crimp Terminal Retention to Housing				N/A ermolo	i		
*On S	3 ckt configuration, 1 of th	e ckts is ground	(pre-mate	e) Above for	rces ar	e peak force	١.	
						6 AWG	8 AWG	10 AW
F C	Odmin Tan i 14 Min	· Dulle "	U N	Avg (lbs)		315	302	216
Force Gauge	Force Gauge Crimp Terminal to Wire Pull Force (lbs) Std Dev 11.17		5.06	4.45				
				Failure M	ode	Wire Pull-out	Wire Break	Wire Break
VISION: ECR/ECN INFO			Gı	uardian	)			EET No.
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## 4.2 MECHANICAL TEST: FREE HANGING LOAD TEST (MATED CONDITION - 2.5 M CABLE)

EQUIPMENT/FIXTURE	TEST DESCRIPTION	TEST RESULT
Rigid Fixture	100 Newtons Weight Straight Inline Loading For 60 Seconds (See Figure 1)	Visually Inspected No Damage
Rigid Fixture	200 Newtons Weight at 90 degrees Loading For 60 Seconds (Both North-South and East-West directions – see Figure 2)	Visually Inspected No Damage
Rigid Fixture	150 Newtons Weight 45 degrees loading For 60 Seconds (See Figure 3)	Visually Inspected No Damage

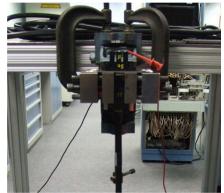






Fig. 1 Fig. 2 Fig. 3

## 5.0 ELECTRICAL REQUIREMENTS

## **5.1 CRIMP STRESS TEST-MILLIVOLT DROP**

CRIMP WIRE SIZE	TEST DESCRIPTION	SAMPLE SIZE	Δ RESULT
	<ul><li>Initial Voltage Drop</li><li>Thermal Shock</li><li>Vibration</li></ul>	Qty 75 Nominal Crimp Height (Grp A)	0.30 Millivolts $\sigma = 0.053$
8 AWG	<ul> <li>Accelerated Aging</li> <li>Final Voltage Drop</li> <li>End Testing</li> </ul>	Qty 30 Upper Crimp Height (Grp. B)	$0.20$ Millivolts $\sigma = 0.045$
	Applied 10 Amps See Figure 4 & 5 for test setup and measurements	Qty 30 Lower Crimp Height (Grp C)	$0.45$ Millivolts $\sigma = 0.101$

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	<ul><li>Initial Voltage Drop</li><li>Thermal Shock</li><li>Vibration</li></ul>	Qty 75 Nominal Crimp Height. (Grp A)	0.66 Millivolts σ = 0.118
10 AWG	<ul> <li>Accelerated Aging</li> <li>Final Voltage Drop</li> <li>End Testing</li> </ul>	Qty 30 Upper Crimp Height (Grp. B)	$0.76$ Millivolts $\sigma = 0.177$
	Applied 10 Amps See Figures 4 & 5 for test set-up and measurements	Qty 30 Lower Crimp Height (Grp C)	0.56 Millivolts σ =0.120

<sup>\*</sup> Acceptance criteria appears on page 4 of this specification

### **5.1.1 CRIMP STRESS ACCEPTANCE CRITERIA**

 $\Delta$  = Change in Millivolts after test sequence

 $\sigma$  = Standard Deviation

Requirements to pass 8 AWG wire:

 $\Delta$  = Average Change + 5.46  $\sigma$  </= 1.33 Millivolt (Group A)

 $\Delta$  = Average Change + 4.21  $\sigma$  </= 1.33 Millivolt (Group B & C)

Requirements to pass 10 AWG wire:

 $\Delta$  = Average Change + 5.46  $\sigma$  </= 1.68 Millivolt (Group A)

 $\Delta$  = Average Change + 4.21  $\sigma$  </= 1.68 Millivolt (Group B & C)



Test Set-up Fig. 4

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## PRODUCT SPECIFICATION

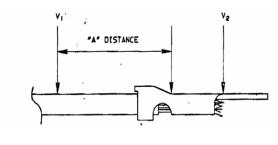


Fig. 5 Voltage Drop

The specimen wire gauge used for testing was 10 AWG. The specimen was powered at 10 amps. Voltage drop measurements were taken after 30 seconds across individual circuits at the applied current. The maximum allowable distance 'A' between the voltage probes was 100 mm. The open circuit voltage may not exceed 0.05 volts. Instrumentation shall be such that the measured value is accurate to +/- 5%.

#### **5.2 ELECTRICAL PERFORMANCE & RATING:**

#### **5.2.1 VOLTAGE:**

Voltage: 600 V Max.

#### **Connector Rating per UL-1977**

Connector voltage rating meets the connector approval level defined by UL 1977, Sect. 11 for spacing's per table 11.1. Example: 1.2 mm for ≥ 250 volt, 3.2 mm for ≤ 250 volt.

Exception taken for spacing less than those specified are permitted if the device complies with the requirements in the dielectric voltage withstanding test per Sect. 17.

### **Application Voltage Guideline**

For application voltage requirements per UL-60950 or other standards, the creepage & clearance also needs to be determined based upon pads/traces on the pcb. For example, per UL-60950-1 (Table 2N) (UL/ANSI Standard-Safety for Information Technology Equipment Requirements) below are the minimum creepage distances required:

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		POLLUTION	DEGREE 2			
RMS Working	MATERIAL GROUP					
Voltages Up to & Including:	PRINTED CIRCUIT BOARDS	OTHER MATERIALS				
	I, II, IIIa, IIIb (mm)	l (mm)	II (mm)	IIIa, IIIb (mm)		
50	.04	0.6	0.85	1.2		
125	.25	0.75	1.05	1.5		
250	1.0	1.25	1.8	2.5		
320	1.6	1.6	2.2	3.2		
630	3.2	3.2	4.5	6.3		

- \*Pollution degree 2 is a typical environment for electrical connectors.
- \*\*Material Group depends on the comparative tracking index (CTI) and is classified as follows:

Material Group I CTI > 600 Material Group II 400 < CTI < 600 Material Group IIIA 175 ≤ CTI < 400 Material Group IIIB 100 < CTI < 175

#### **5.2.2 OPERATING TEMPERATURE**

Operating temperature (including T-rise from applied current) is -40°C to +105°C. Field temperatures and field life: Tested per EIA-364-1000.01 (see pg 14) to meet field temperature of 65° C for 10 years or 85° C for 3 years per Tables 8 & 9 application guideline.

#### **5.2.3 CURRENT:** (See Item #4)

Current rating is application dependent. The ratings listed in the chart are per EIA364-70 and should be used as a guideline only. Appropriate de-rating is required per ckt size, ambient conditions, copper trace size on the PCB, gross heating from adjacent modules or components, and other factors that influence connector performance. Wire size and stranding, tin coated or bare copper, wire length & crimp quality are other factors that influence current rating

#### 5.2.4 DURABILITY WITH ENVIRONMENT:

25 cycles on EIA 364-1000.01 Group 4 Test sequence.

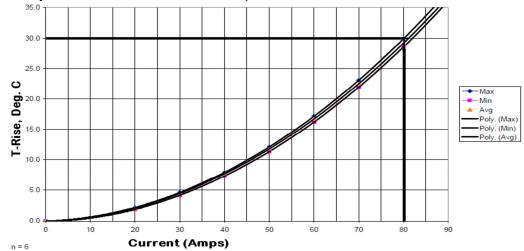
REVISION:		TITLE:	Guardian				
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## PRODUCT SPECIFICATION

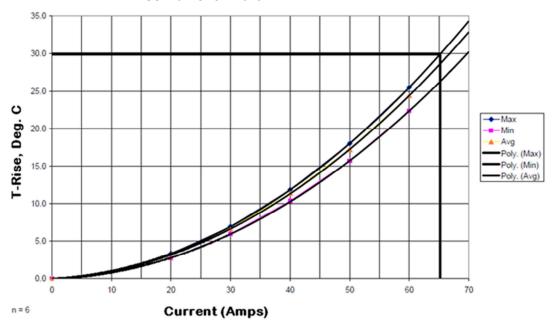
### 5.3 TEMPERATURE RISE & VOLTAGE DROP CHARTS

## 5.3.1 EPIC, 1-Circuit, 6 AWG Wire, 0.050" Cu T-Rise Current Chart

## \*Extrapolation based on 1-2 ckt test, no test data available



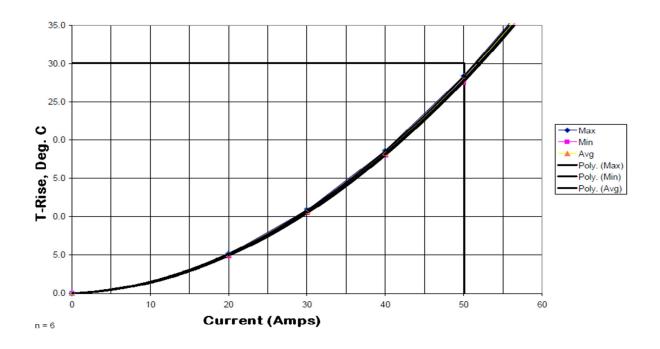
## 5.3.2 EPIC, 1-circuit, 8 AWG Wire, 0.032" Cu T-Rise Current Chart



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## 5.3.3 EPIC, 1-circuit, 10 AWG Wire, 0.026" Cu T-Rise Current Chart



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## 5.3.4 EPIC, 2-Circuit, 8 AWG Wire, 0.032" Cu Voltage Drop vs. Current

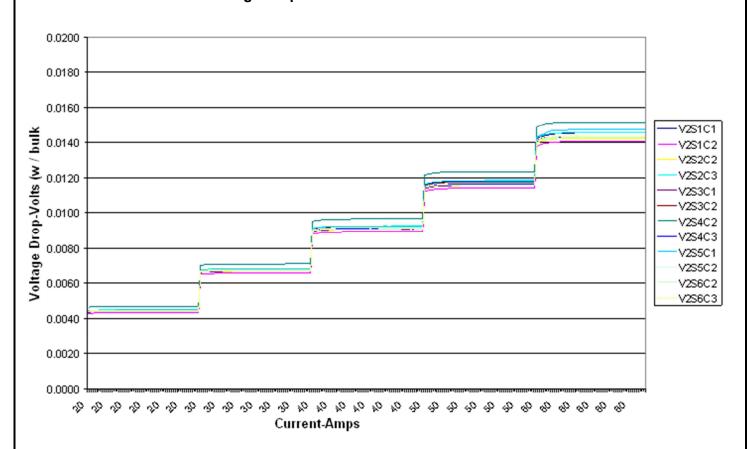


Fig. 6

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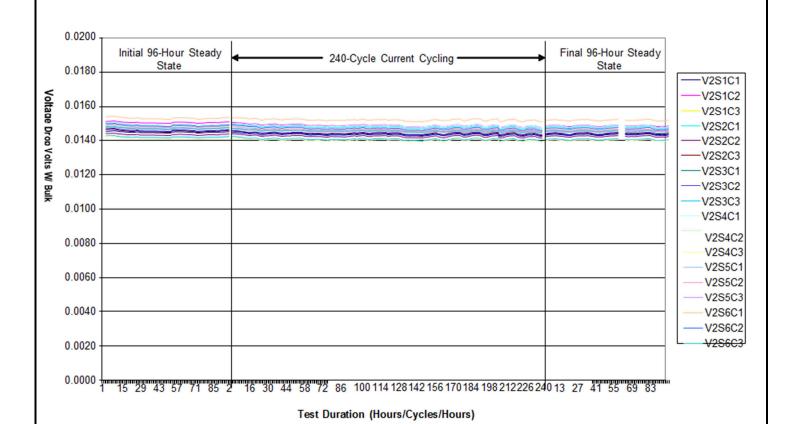


Fig. 7

NOTE: Current Cycle Duration is 1 hour (45 minutes on and 15 minutes off)

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## PRODUCT SPECIFICATION

## 6.0 TEST PLAN, ENVIRONMENTAL TEST PER EIA-364-1000.01 - Table 8

Group Temperatur (30 conta	re Life	Group II Thermal Sho (30 contact		Group III Vibration (30 contacts)	Group IV Flowing Mixed Gas (402 contacts)	Group V Thermal Cycling (30 contacts)
Initial Con Resistan		Initial Conta Resistance		Initial Contact Resistance	Initial Contact Resistance	Initial Contact Resistance
EIA-364-	-23	EIA-364-23	3	EIA-364-23	EIA-364-23	EIA-364-23
Durabili 5 cycle		Durability 5 cycles		Durability 5 cycles	Durability 5 cycles	Durability 5 cycles
EIA-364-	-09	EIA-364-09	)	EIA-364-09	EIA-364-09	EIA-364-09
Contact Res	istance	Contact Resista	ance	Contact Resistance	Contact Resistance	Contact Resistance
Temperatur 105°C, 240 10 Yrs @ 0	hours	Thermal Sho 10 cycles -55°C and +89		Temperature Life 105°C, 120 hours 10 Yrs @ 65°C	Temperature Life 105°C, 120 hours 10 Yrs @ 65°C	Temperature Life 105°C, 120 hours 10 Yrs @ 65°C
EIA-364-	-17	EIA-364-32	2	EIA-364-17	EIA-364-17	EIA-364-17
Contact Res	istance	Contact Resista	ance	Contact Resistance	Contact Resistance	Contact Resistance
Reseati		Cyclic Tempera		Random Vibration	Flowing Mixed Gas 10 days unmated	Thermal Cycling
3 cycle	es	EIA-364-31		EIA-364-28 Condition VIID	EIA-364-65	EIA-364-1000.01
Contact Res	istance	Contact Resista	ance	Contact Resistance	Contact Resistance	Contact Resistance
		Reseating 3 cycles			Flowing Mixed Gas 4 days mated	Reseating 3 cycles
					EIA-364-65	
		Contact Resista	ance		Contact Resistance	Contact Resistance
					Thermal Disturbance	
					EIA-364-1000.01  Contact Resistance	] ]
					Reseating	]
					3 cycles	
					Contact Resistance	]
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CREATED / REVISED BY:

**J.QUILES** 

CHECKED BY:

J.SCHAFER

**APPROVED BY:** 

A.PATEL

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## PRODUCT SPECIFICATION

## 7.0 TEST RESULTS, ENVIRONMENTAL TESTING - Table 9

EIA-364-TS-1000 - Group 1 Testing						
	Initial	Durability 5X	T. Life	Reseating 3X		
	mΩ	ΔmΩ	$\Delta m\Omega$	ΔmΩ		
Min	0.387	-0.010	0.001	0.002		
Max	0.649	0.008	0.024	0.032		
Avg	0.506	0.000	0.014	0.018		
St. Dev.	0.081	0.004	0.006	0.007		
n	36	36	36	36		

	EIA-364-TS-1000 - Group 2 Testing							
	Initial	Durability 5X	T. Shock	C. Humidity	Reseating 3X			
	mΩ	ΔmΩ	ΔmΩ	ΔmΩ	ΔmΩ			
Min	0.419	-0.054	-0.056	-0.050	-0.039			
Max	0.681	0.155	0.163	0.156	0.162			
Avg	0.490	0.012	0.017	0.020	0.019			
St. Dev.	0.066	0.046	0.047	0.045	0.044			
n	36	36	36	36	36			

EIA-364-TS-1000 - Group 3 Testing							
	Initial	Initial Durability 5X	T. Life	Random Vibration			
	mΩ	ΔmΩ	ΔmΩ	ΔmΩ			
Min	0.374	-0.007	0.004	-0.010			
Max	0.651	0.013	0.028	0.041			
Avg	0.524	0.001	0.017	0.009			
St. Dev.	0.073	0.004	0.005	0.011			
n	36	36	36	36			

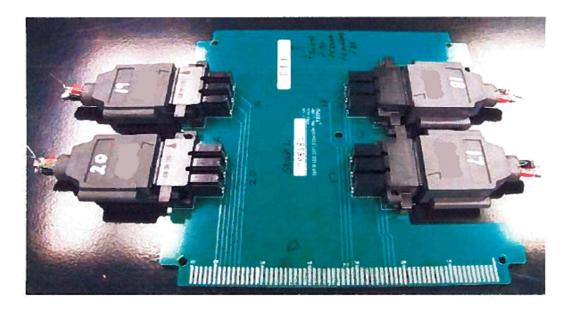
EIA-364-TS-1000 - Group 5 Testing							
	Initial	Durability 5X	T. Life	Thermal Cycling	Reseating 3X		
	mΩ	ΔmΩ	$\Delta$ m $\Omega$	ΔmΩ	ΔmΩ		
Min	0.343	-0.006	0.007	-0.001	0.004		
Max	0.672	0.009	0.043	0.041	0.038		
Avg	0.504	0.000	0.019	0.010	0.019		
St. Dev.	0.093	0.003	0.007	0.008	0.010		
n	36	36	36	36	36		

<sup>\*</sup> Note: resistance includes bulk, interface and crimp. Above resistance data includes 0.24 milliohms for Power and 0.29 milliohms for ground from wire length 7 test set-up. See sample preparation detail on page 10 of this specification.

<sup>\*\*</sup> Applied current <1.0 Amp for LLCR

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## PRODUCT SPECIFICATION



Test Set-up for EIA-364-1000.01 Sequences 1, 2, 3 & 5

Fig. 10

#### **SAMPLE PREPARATION**

The headers were wave soldered onto the PC boards and cleaned in the parts washer. The plugs were common bussed so LLCR measurements could be made. Due to sample preparation there is some added bulk resistance added in the measurements. There is approximately 1.75 inches of 8 AWG for the power contacts and 1.75 inches of 10 AWG wire for the ground contacts. This contributes ~0.09 milliohms of bulk resistance to the power contact measures and ~0.144 milliohms to the ground measures. The measurement leads (pigtail) also add up to 0.15 milliohms of additional bulk for a total of around 0.24 milliohms power, and 0.29 milliohms ground (See Figure 10).

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## PRODUCT SPECIFICATION

## **EIA-364-1000 Test Group 4**

Description: 3 circuit board mount plug and cable receptacle

**Reference Information** 

Environmental Test Methodology...

EIA-364-1000 (Test Group 4)

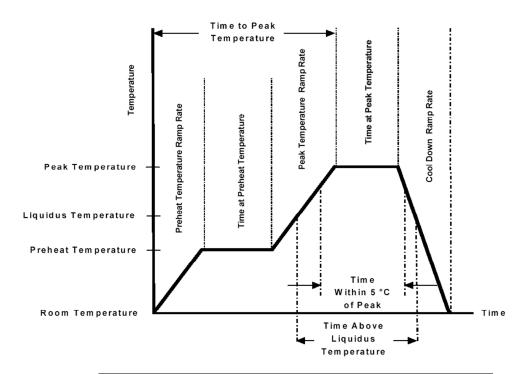
## **Contact Reliability**

Cell	Description	Conditions	Duration	Order	Samples
1	LLCR	4-wire, dry circuit, 20 mV max		1	1-134
	Durability (pre- conditioning)	mate / unmate	5 cycles	2	all
2	LLCR	4-wire, dry circuit, 20 mV max		3	all
	Temperature Life (pre-conditioning)	105C	120 hours	4	all
3	LLCR	4-wire, dry circuit, 20 mV max		5	all
	MFG Exposure	Unmated (board mount plugs only)	10 days	6	all
4	LLCR	4-wire, dry circuit, 20 mV max		7	all
	MFG Exposure	Mated	4 days	8	all
5	LLCR	4-wire, dry circuit, 20 mV max			
	Disturbance (ATC)	15C / 85C	10 cycles	9	all
6	LLCR	4-wire, dry circuit, 20 mV max		10	all
	Reseat **	mate / unmate	3 cycles	11	all
7	LLCR **	4-wire, dry circuit, 20 mV max		12	all

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#### 8.0 **SOLDERING PROFILE**

(This profile is per JEDEC J-STD-020D.1 and it is for guide line only; please see notes for additional information)



Description	Requirement
Average Ramp Rate	3°C/sec Max
Preheat Temperature	150°C Min to 200°C Max
Preheat Time	60 to 180 sec
Ramp to Peak	3°C/sec Max
Time over Liquids (217°C)	60 to 150 sec
Peak Temperature	260 +0/-5°C
Time within 5°C of Peak	20 to 40 sec
Ramp - Cool Down	6°C/sec Max
Time 25°C to Peak	8 min Max

#### Note:

1. Temperature indicated refers to the PCB surface temperature at solder tail area.

#### THIS PRODUCT IS NOT DESIGNED FOR IR REFLOW PROCESS

REVISION:	ECR/ECN INFORMATION: EC No: UCP2013-5363  DATE: 2013/06/12	TITLE:	17 of 19		
DOCUMENT NUMBER:		CREATED / REVISED BY:	CHECKED BY:	APPRO\	/ED BY:
PS-46819-001		J.QUILES	J.SCHAFER	A.PA	TEL
TEMPLATE FILENAME: PRODUCT SPECISIZE AI(V, 1) DOC					

9.1

## PRODUCT SPECIFICATION

#### 9.0 SAFETY AGENCY RATING APPROVAL:

Covers product series 46817, 46818, 170351



c US File Number\*: LR-19980

Single Ckt.	Current	Voltage
6 AWG	80 Amps	600 VDC
8 AWG	60 Amps	600 VDC

CSA approval meets following standards/test procedures:

a) CSA std. C22.2 No. 182.3

b) UL-1977

 "C" and "US" mark adjacent to CSA signifies that the product has been evaluated to the applicable CSA and ANSI/UL standards, for use in Canada and US respectively.

## 9.2 U.L. File No. E29179 Rev. 2012-09-24 Volume 10, Sec. 18, Page 1

AWG	Voltage (V)	Current (I)
6	600 AC	80 Amps
8	600 AC	65 Amps
10	600 AC	50 Amps

Flammability - V-0

Note: Approval is at the component level.

### 9.2.1 Hot-Plug / Overload:

250 Volt AC @ 80 Amps tested to 25 cycles.

REVISION:	ECR/ECN INFORMATION: EC No: UCP2013-5363 DATE: 2013/06/12	Guardian Wire to Board Interconnect System			SHEET No. 18 of 19
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## PRODUCT SPECIFICATION

## 9.2.2 HOT-MATE/RESISTANCE TO ARC RATING SYSTEM:

Tested 8 AWG 350 VDC @ 12 Amp. Conducted 50 cycle followed by T-rise max, T-rise is 30°C.

ITEM	TEST DESCR	IPTION	RESULT				
1	Initial Contact Resistance (Low Level)	6 AWG 8 AWG 10 AWG	See Table 9				
2	Dielectric Withstanding for 60 sec. @ 5mAmp max. per EIA-364-52	1,700 VAC	Pass				
3	Insulation Resistance for 60 sec. @ 500 VDC	1,000 MegOhms	Pass				
4	T-Rise	rent carrying Capability @ 30 degree T-Rise Per EIA-70		1 Ckt (Amps) 80 65 50	2 Ckt (Amps) 77 62 48	3 Ckt (Amps) 73 58 44	4-6Ckt * (Amps) 63 50 35
5	Reliability Test for 6 AWG @ 30 degree T- Rise Max ( 3ckt Power)	70 Amps for 4 days, current cycle for 10 days, 70 amps for 4 additional days	Stable for entire test duration (See 5.3.5 - Fig 7)				
6	Voltage Drop with Step Current applied per EIA 364, TP-06	2 Ckt. With 8 AWG Wire	16	Millivolt dro	op max (Se	e 5.3.4 - F	ig 6)

## 9.2.3 Current Interrupt Rating Per UL-1977 is 30Amps @ 250VAC

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C 4	EC No: UCP2013-5363	,	Wire to Board		<b>19</b> of <b>19</b>
C4	DATE: 2013/06/12	Inte			
DOCUMENT NUMBER:		CREATED / REVISED BY:	CHECKED BY:	APPRO\	ED BY:
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